GL21N50A8

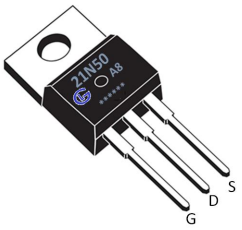
Silicon N-Channel Power MOSFET

V_{DSS}(T_C=150℃)	500	V
I_D	21	A
P_D(T_C=25℃)	230	W
$R_{DS(ON).type.}$	0.21	Ω

General Description

GL21N50A8, the silicon N-channel Enhanced VDMOSFET, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is TO-220AB, which accords with the RoHS standard.

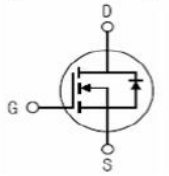
TO-220



Features

- Fast Switching
- Low ON Resistance(Typical Data:0.21Ω)
- Low Gate Charge Minimize Switching loss
- Fast Recovery Body Diode
- 100% Single Pulse avalanche energy Test

Inner Equivalent Principium Chart



Applications

- Adaptor
- Charger
- SMPS Standby Power

Absolute (Tc=25℃ unless otherwise specified)

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage[*1]	500	V
I_D	Continuous Drain Current	21	A
I_{DM}	Pulsed Drain Current at V_{GS}=10V[*2]	84	A
V_{GS}	Gate-to-Source Voltage	±30	V
E_{AS}	Single Pulse Avalanche Energy	1500	mJ
I_{AS}	Avalanche Current	6.8	A
dv/dt	Peak Diode Recovery dv/dt[*3]	5.0	V/ns
P_D	Power Dissipation	230	W
	Derating Factor above 25°C	1.84	W/℃
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150,–55 to 150	℃
T_L	Maximum Temperature for Soldering	300	℃

Caution Stresses greater than those in the "Absolute Maximum Ratings" may cause permanent damage to the device

Thermal Characteristics

Symbol	Parameter	Rating	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.54	℃/ W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	40	℃/ W

Electrical Characteristics (Tc= 25℃ unless otherwise specified)

OFF Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	V_{GS}=0V,I_D=250μA	500	--	--	V
I_{DSS}	Drain to Source Leakage Current	V_{DS}=500V, V_{GS}=0V,T_a=25℃	--	--	1.0	μA
		V_{DS}=400V, V_{GS}=0V,T_a=125℃	--	--	100	
$I_{GSS(F)}$	Gate to Source Forward Leakage	V_{GS}=+30V	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	V_{GS}=-30V	--	--	-100	nA

ON Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance*4	V_{GS}=10V,I_D=10.5A	--	0.21	0.25	Ω
$V_{GS(TH)}$	Gate Threshold Voltage	V_{DS}=V_{GS},I_D=250μA	2.0	--	4.0	V
g_{fs}	Forward Transconductance*4	V_{DS}=15V,I_D=10.5A	--	17	--	S

Dynamic Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
C_{iss}	Input Capacitance	V_{GS}=0V V_{DS}=25V f=1.0MHz	--	2864	--	pF
C_{oss}	Output Capacitance		--	286	--	
C_{rss}	Reverse Transfer Capacitance		--	25	--	

Resistive Switching Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	I_D=21A,V_{DD}=250V V_{GS}=10V,R_g=25Ω	--	33	--	ns
t_r	Rise Time		--	75	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	181	--	
t_f	Fall Time		--	83	--	
Q_g	Total Gate Charge	I_D=21A,V_{DD}=250V V_{GS}=10V	--	63	--	nC
Q_{gs}	Gate to Source Charge		--	14	--	
Q_{gd}	Gate to Drain (“Miller”)Charge		--	24	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_{SD}	Continuous Source Current (Body Diode)		--	--	21	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	80	A
V_{SD}	Diode Forward Voltage	I_S=21A,V_{GS}=0V	--	--	1.5	V
t_{rr}	Reverse Recovery Time	I_S=21A,T_j=25℃	--	392	--	ns
Q_{rr}	Reverse Recovery Charge	dI_F/dt=100A/μs,V_{GS}=0V	--	3.36	--	uC

*1: T_J = +25℃to +150℃

*2: Repetitive rating; pulse width limited by maximum junction temperature.

*3: I_{SD}=21A,di/dt<100A/μs,V_{DD}<BV_{DSS},T_J=+150℃.

*4: Pulse width<380μs; duty cycle<2%.

Characteristics Curves

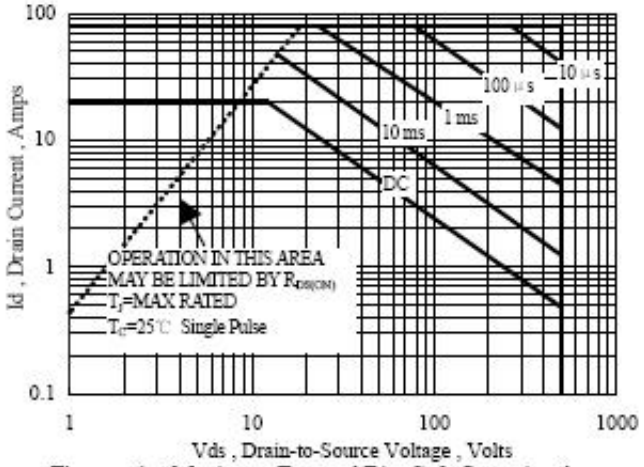


Figure 1 Maximum Forward Bias Safe Operating Area

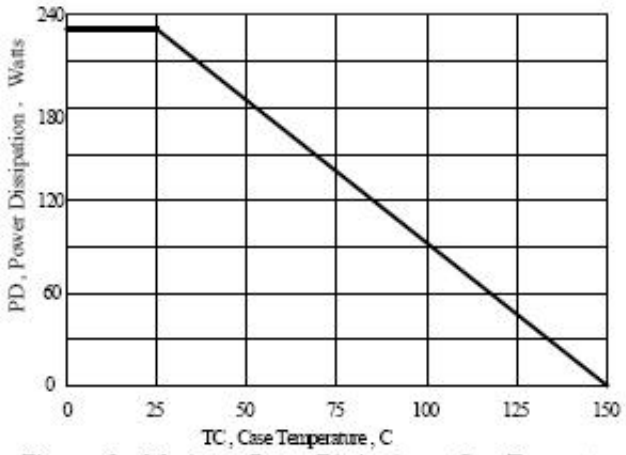


Figure 2 Maximum Power Dissipation vs Case Temperature

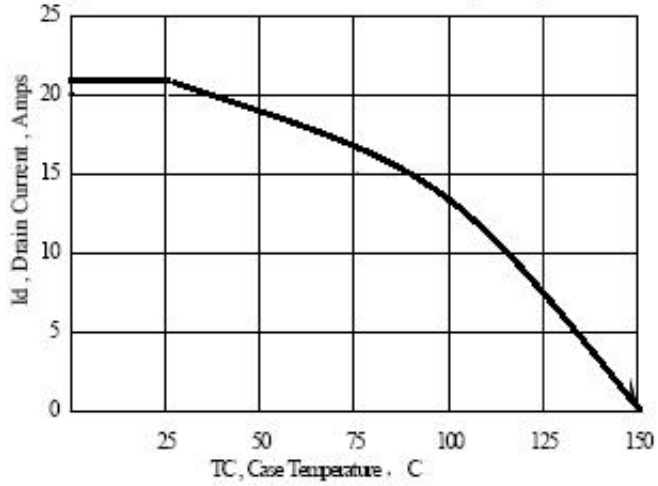


Figure 3 Maximum Continuous Drain Current vs Case Temperature

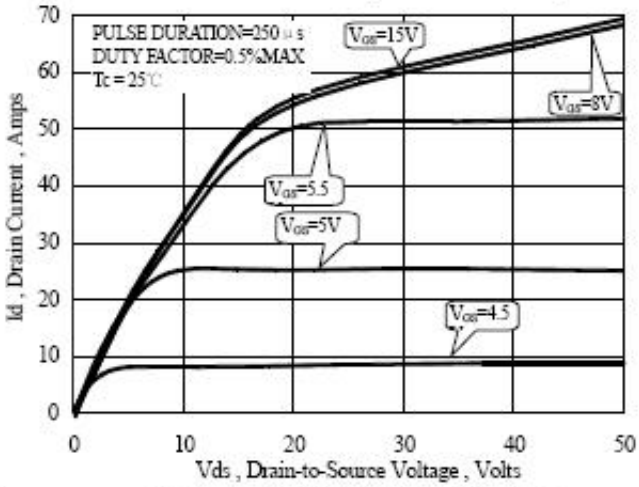


Figure 4 Typical Output Characteristics

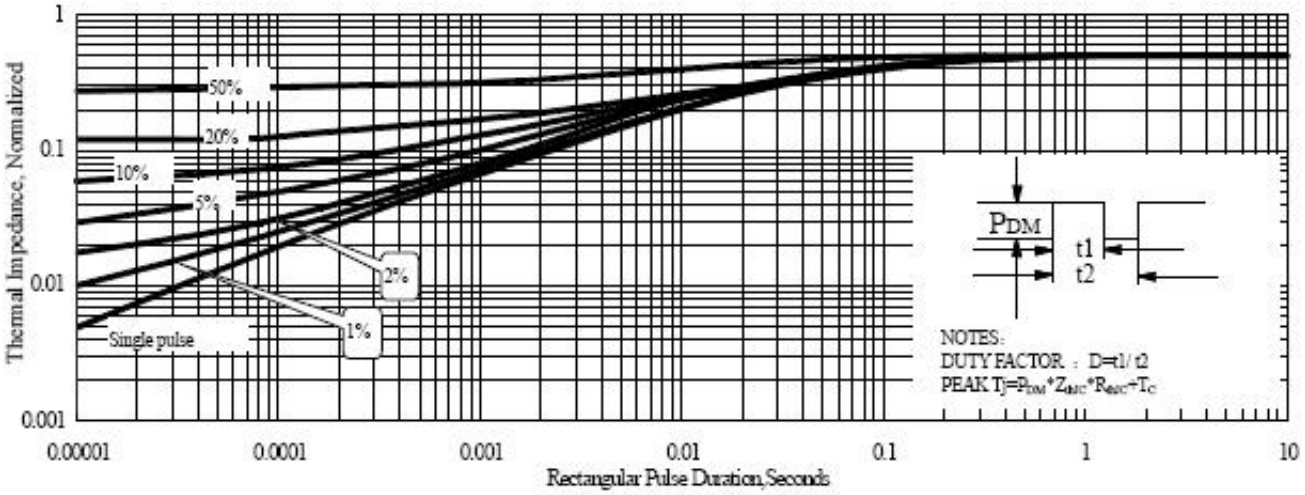


Figure 5 Maximum Effective Thermal Impendance , Junction to Case

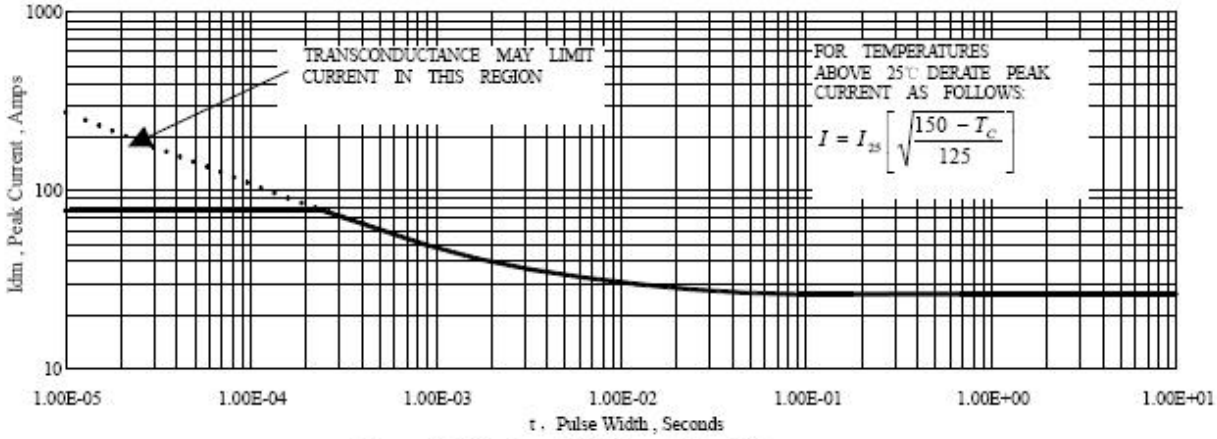


Figure 6 Maximum Peak Current Capability

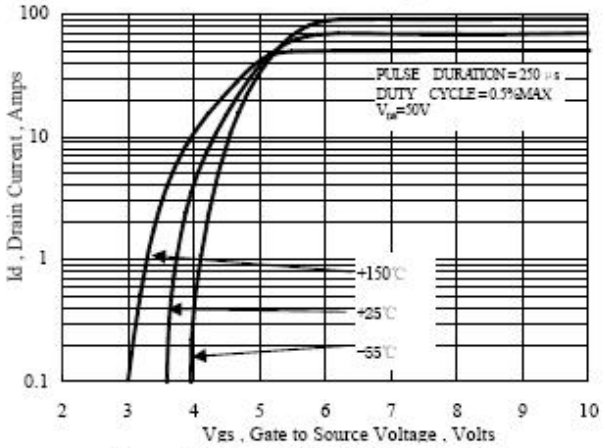


Figure 7 Typical Transfer Characteristics

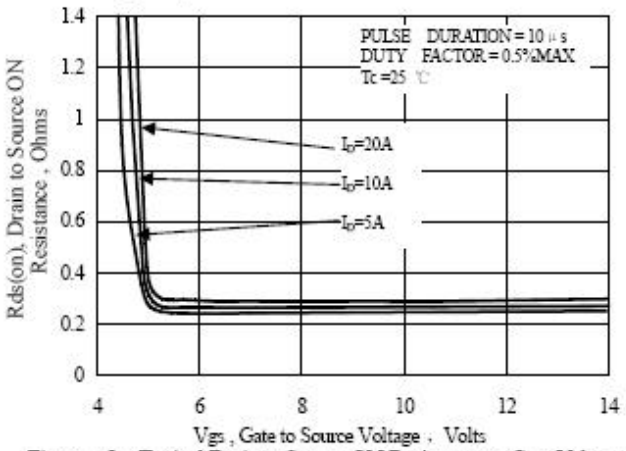


Figure 8 Typical Drain to Source ON Resistance vs Gate Voltage and Drain Current

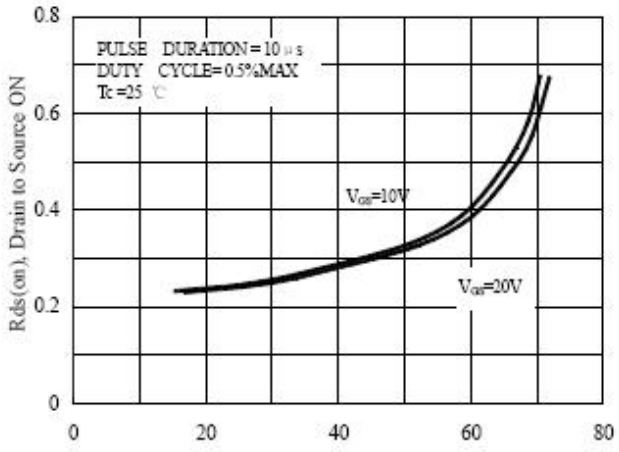


Figure 9 Typical Drain to Source ON Resistance vs Drain Current

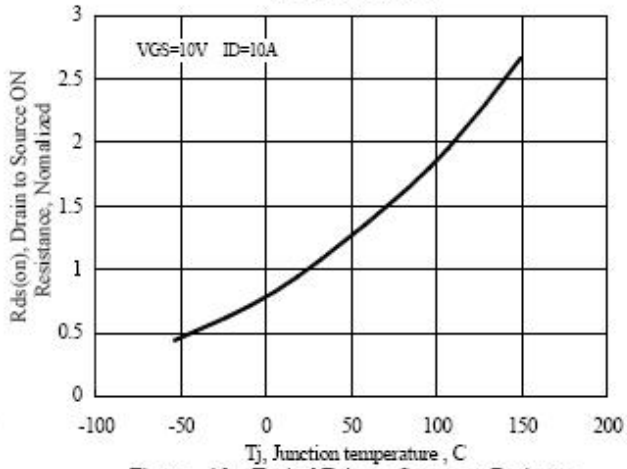


Figure 10 Typical Drian to Source on Resistance vs Junction Temperature

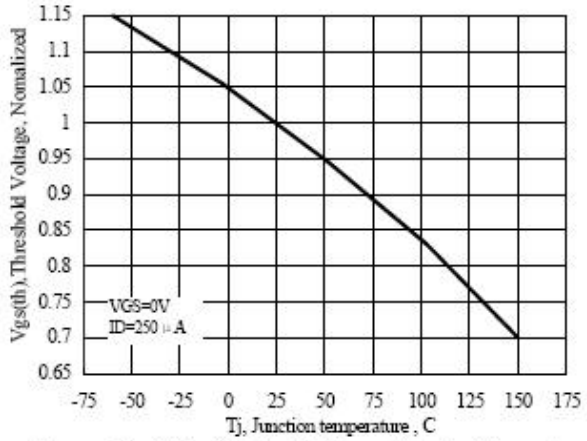


Figure 11 Typical Theshold Voltage vs Junction Temperature

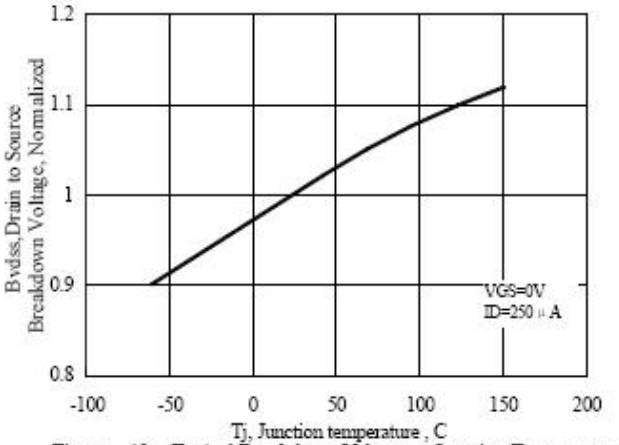


Figure 12 Typical Breakdown Voltage vs Junction Temperature

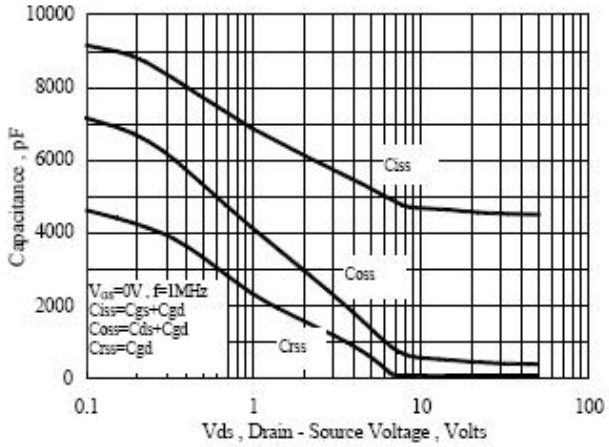


Figure 13 Typical Capacitance vs Drain to Source Voltage

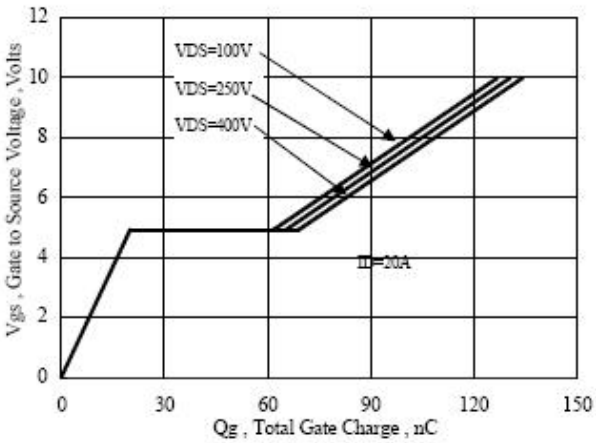


Figure 14 Typical Gate Charge vs Gate to Source Voltage

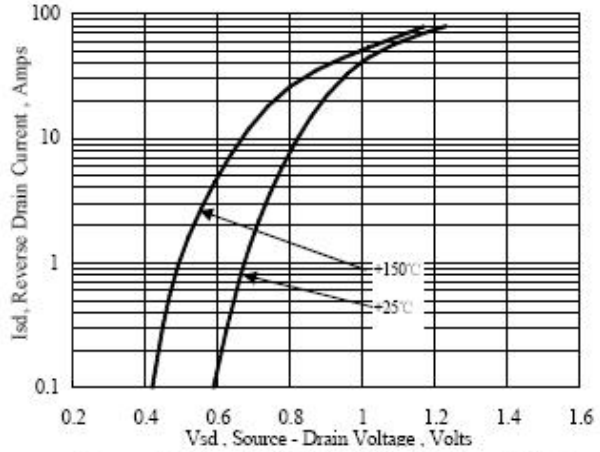


Figure 15 Typical Body Diode Transfer Characteristics

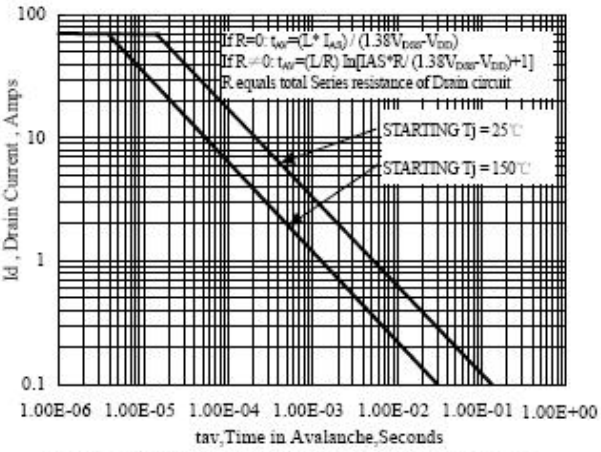


Figure 16 Unclamped Inductive Switching Capability